

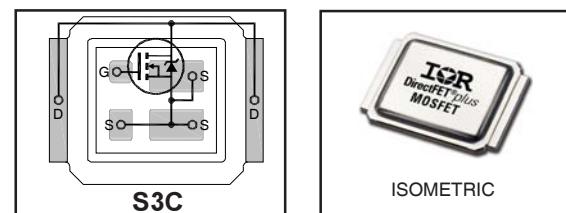
IRF6892STRPbF IRF6892STR1PbF

- RoHS Compliant and Halogen Free ①
- Low Profile (<0.7 mm)
- Dual Sided Cooling Compatible ①
- Ultra Low Package Inductance
- Optimized for High Frequency Switching ①
- Ideal for CPU Core DC-DC Converters
- Optimized for Control FET Application ①
- Compatible with existing Surface Mount Techniques ①
- 100% R_g tested

DirectFET®*plus* MOSFET with Schottky Diode ②

Typical values (unless otherwise specified)

V _{DSS}	V _{GS}	R _{DS(on)}	R _{DS(on)}		
25V max	±16V max	1.3mΩ @ 10V	2.0mΩ @ 4.5V		
Q _{g tot}	Q _{gd}	Q _{gs2}	Q _{rr}	Q _{oss}	V _{gs(th)}
17nC	6.0nC	2.3nC	39nC	16nC	1.8V



Applicable DirectFET Outline and Substrate Outline ①

S1	S2	S3C	M2	M4	L4	L6	L8

Description

The IRF6892SPbF combines the latest HEXFET® Power MOSFET Silicon technology with the advanced DirectFET™ packaging to achieve the lowest on-state resistance in a package that has the footprint of a SO-8 and less than 0.7 mm profile. The DirectFET package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques. Application note AN-1035 is followed regarding the manufacturing methods and processes. The DirectFET package allows dual sided cooling to maximize thermal transfer in power systems, improving previous best thermal resistance by 80%.

The IRF6892SPbF balances industry leading on-state resistance while minimizing gate charge along with low gate resistance to reduce both conduction and switching losses. This part contains an integrated Schottky diode to reduce the Q_{rr} of the body drain diode further reducing the losses in a Synchronous Buck circuit. The reduced losses make this product ideal for high frequency/high efficiency DC-DC converters that power high current loads such as the latest generation of microprocessors. The IRF6892SPbF has been optimized for parameters that are critical in synchronous buck converter's Sync FET sockets.

Absolute Maximum Ratings

	Parameter	Max.	Units
V _{DS}	Drain-to-Source Voltage	25	V
V _{GS}	Gate-to-Source Voltage	±16	
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V ③	28	A
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ 10V ③	22	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V ④	125	
I _{DM}	Pulsed Drain Current ⑤	220	
E _{AS}	Single Pulse Avalanche Energy ⑥	240	mJ
I _{AR}	Avalanche Current ⑤	22	A

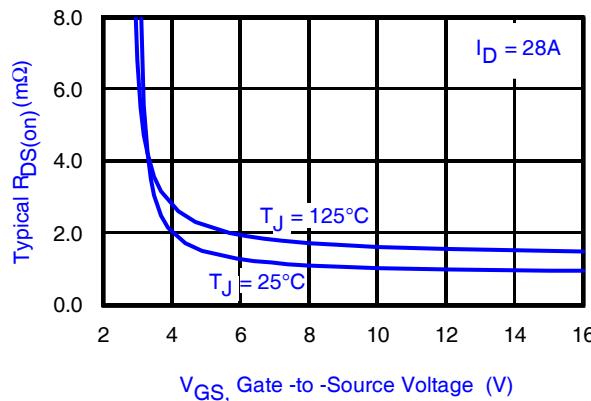


Fig 1. Typical On-Resistance vs. Gate Voltage

Notes:

- ① Click on this section to link to the appropriate technical paper.
- ② Click on this section to link to the DirectFET Website.
- ③ Surface mounted on 1 in. square Cu board, steady state.

www.irf.com

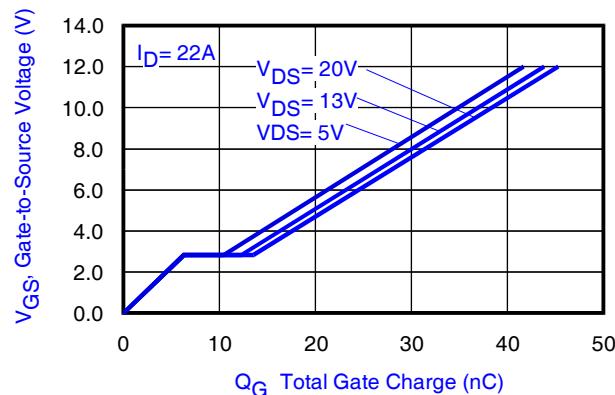


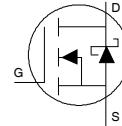
Fig 2. Typical Total Gate Charge vs Gate-to-Source Voltage

- ④ T_C measured with thermocouple mounted to top (Drain) of part.
- ⑤ Repetitive rating; pulse width limited by max. junction temperature.
- ⑥ Starting T_J = 25°C, L = 1.2mH, R_G = 25Ω, I_{AS} = 22A.

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	25	—	—	V	$V_{\text{GS}} = 0\text{V}, I_D = 1\text{mA}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	11	—	mV/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 5\text{mA}$
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance	—	1.3	1.7	$\text{m}\Omega$	$V_{\text{GS}} = 10\text{V}, I_D = 28\text{A}$ ⑦
		—	2.0	2.6		$V_{\text{GS}} = 4.5\text{V}, I_D = 22\text{A}$ ⑦
$V_{\text{GS(th)}}$	Gate Threshold Voltage	1.1	1.8	2.1	V	$V_{\text{DS}} = V_{\text{GS}}, I_D = 50\mu\text{A}$
$\Delta V_{\text{GS(th)}}/\Delta T_J$	Gate Threshold Voltage Coefficient	—	-9.8	—	mV/ $^\circ\text{C}$	
I_{DSS}	Drain-to-Source Leakage Current	—	—	500	μA	$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}$
		—	—	5.0	mA	$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{\text{GS}} = 16\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100	nA	$V_{\text{GS}} = -16\text{V}$
g_{fs}	Forward Transconductance	290	—	—	S	$V_{\text{DS}} = 13\text{V}, I_D = 22\text{A}$
Q_g	Total Gate Charge	—	17	25	nC	$V_{\text{DS}} = 13\text{V}$ $V_{\text{GS}} = 4.5\text{V}$ $I_D = 22\text{A}$ See Fig. 2 & 15
$Q_{\text{gs}1}$	Pre-V _{th} Gate-to-Source Charge	—	4.0	—		
$Q_{\text{gs}2}$	Post-V _{th} Gate-to-Source Charge	—	2.3	—		
Q_{gd}	Gate-to-Drain Charge	—	6.0	—		
Q_{godr}	Gate Charge Overdrive	—	4.7	—		
Q_{sw}	Switch Charge ($Q_{\text{gs}2} + Q_{\text{gd}}$)	—	8.3	—	nC	$V_{\text{DS}} = 10\text{V}, V_{\text{GS}} = 0\text{V}$
Q_{oss}	Output Charge	—	16	—		
R_G	Gate Resistance	—	0.4	—		
$t_{\text{d(on)}}$	Turn-On Delay Time	—	12	—	ns	$V_{\text{DD}} = 13\text{V}, V_{\text{GS}} = 4.5\text{V}$ ⑦ $I_D = 22\text{A}$ $R_G = 1.8\Omega$
t_r	Rise Time	—	30	—		
$t_{\text{d(off)}}$	Turn-Off Delay Time	—	16	—		
t_f	Fall Time	—	9.5	—		
C_{iss}	Input Capacitance	—	2510	—	pF	$V_{\text{GS}} = 0\text{V}$ $V_{\text{DS}} = 13\text{V}$ $f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	850	—		
C_{rss}	Reverse Transfer Capacitance	—	190	—		

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	76	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ⑤	—	—	220	A	
V_{SD}	Diode Forward Voltage	—	—	0.75	V	
t_{rr}	Reverse Recovery Time	—	22	33	ns	
Q_{rr}	Reverse Recovery Charge	—	37	56	nC	

Notes:

⑤ Repetitive rating; pulse width limited by max. junction temperature.

⑦ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.

Absolute Maximum Ratings

	Parameter	Max.	Units
P _D @ T _A = 25°C	Power Dissipation ③	2.1	
P _D @ T _A = 70°C	Power Dissipation ③	1.3	
P _D @ T _C = 25°C	Power Dissipation ④	42	
T _P	Peak Soldering Temperature	270	
T _J	Operating Junction and Storage Temperature Range	-40 to + 150	°C
T _{STG}			

Thermal Resistance

	Parameter	Typ.	Max.	Units
R _{θJA}	Junction-to-Ambient ③⑩	—	60	
R _{θJA}	Junction-to-Ambient ③⑩	12.5	—	
R _{θJA}	Junction-to-Ambient ③⑩	20	—	°C/W
R _{θJC}	Junction-to-Case ④⑩	—	3.0	
R _{θJ-PCB}	Junction-to-PCB Mounted	1.0	—	
	Linear Derating Factor ③	0.016		W/°C

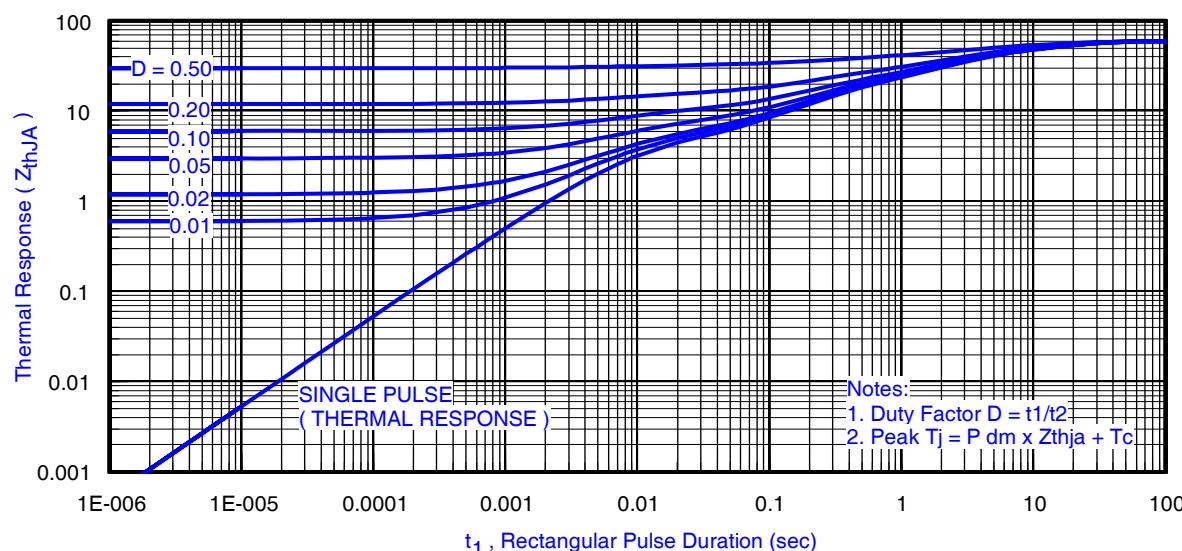
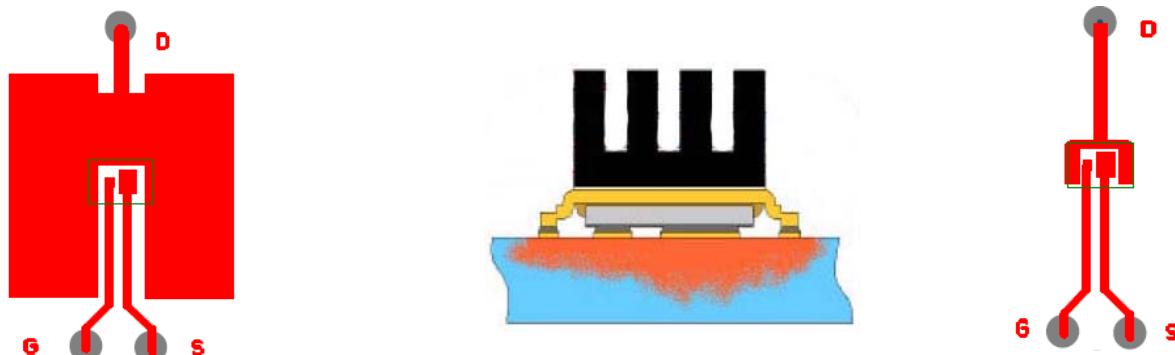


Fig 3. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient ①

Notes:

- ③ Surface mounted on 1 in. square Cu board, steady state.
- ④ T_C measured with thermocouple in contact with top (Drain) of part.
- ⑤ Used double sided cooling, mounting pad with large heatsink.
- ⑥ Mounted on minimum footprint full size board with metalized back and with small clip heatsink.
- ⑦ R_θ is measured at T_J of approximately 90°C.



③ Surface mounted on 1 in. square Cu board (still air).

⑥ Mounted on minimum footprint full size board with metalized back and with small clip heatsink. (still air)

IRF6892STR/TR1PbF

International
Rectifier

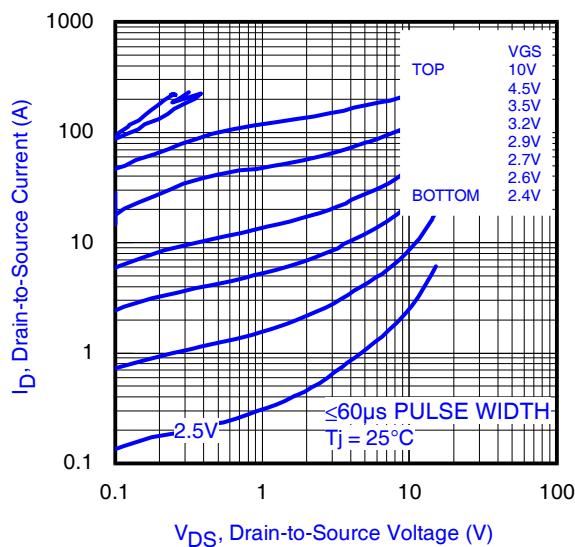


Fig 4. Typical Output Characteristics

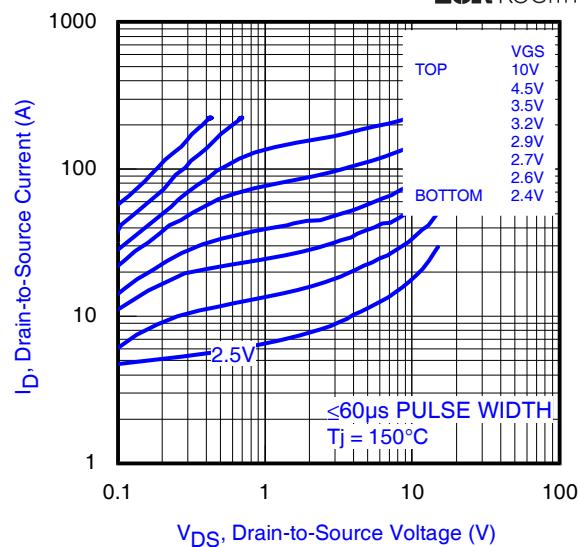


Fig 5. Typical Output Characteristics

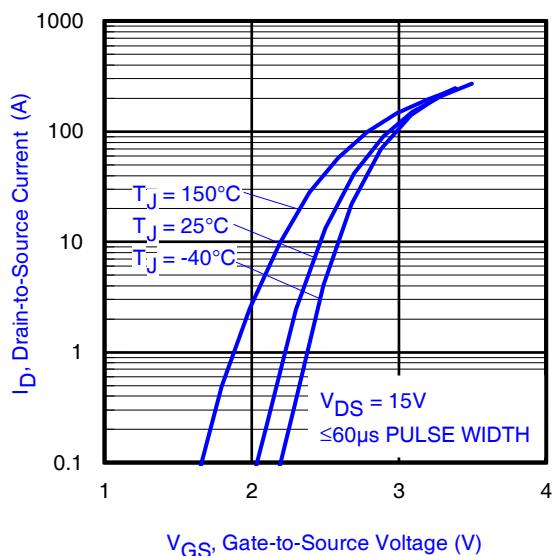


Fig 6. Typical Transfer Characteristics

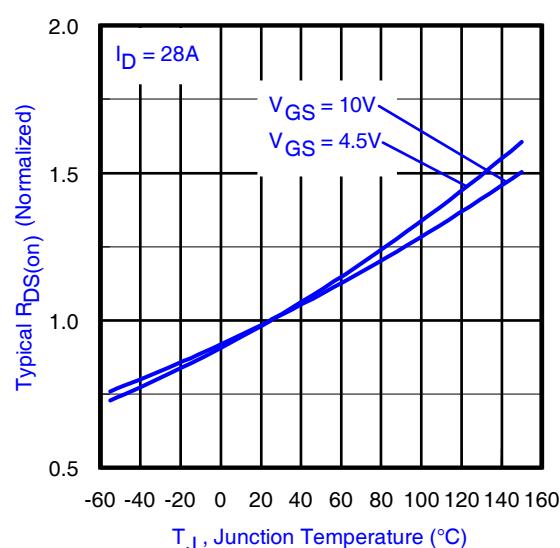


Fig 7. Normalized On-Resistance vs. Temperature

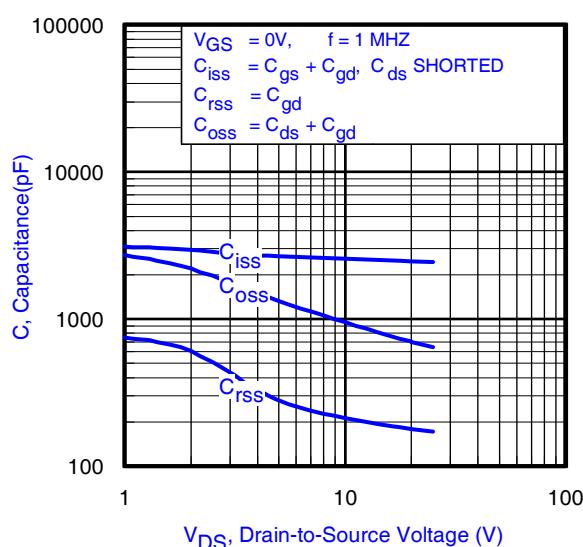


Fig 8. Typical Capacitance vs. Drain-to-Source Voltage

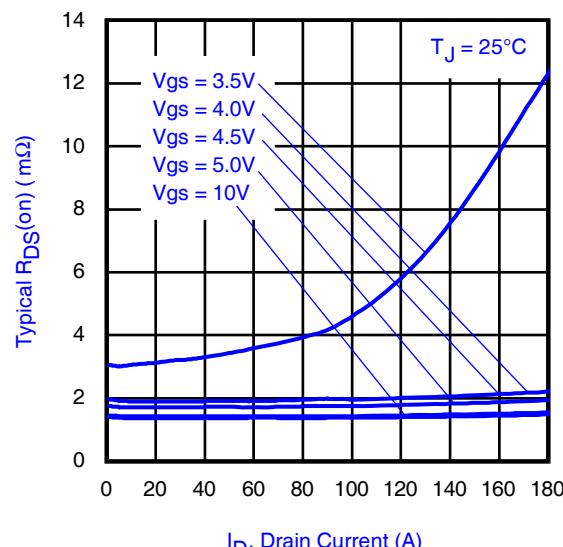


Fig 9. Typical On-Resistance vs. Drain Current and Gate Voltage

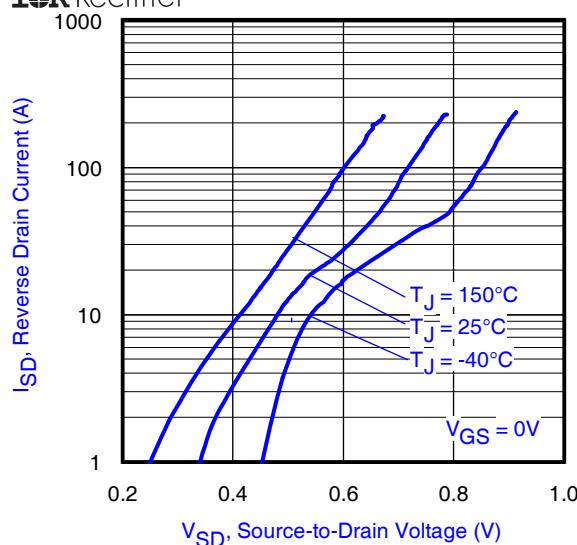


Fig 10. Typical Source-Drain Diode Forward Voltage

IRF6892STR/TR1PbF

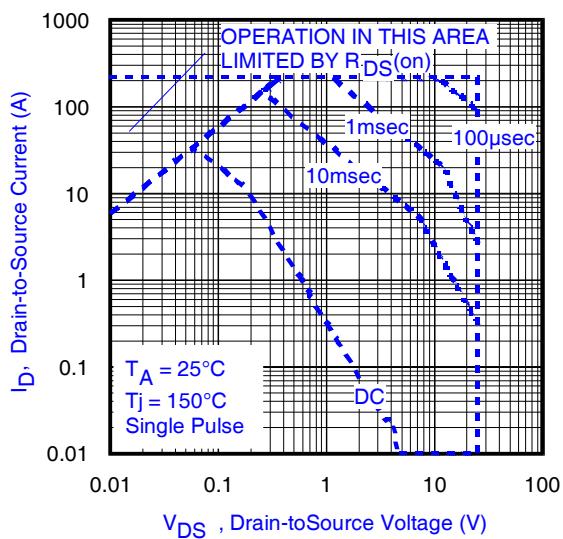


Fig 11. Maximum Safe Operating Area

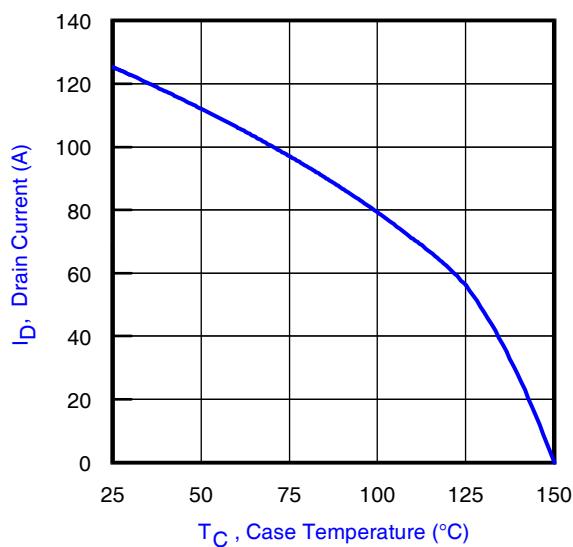


Fig 12. Maximum Drain Current vs. Case Temperature

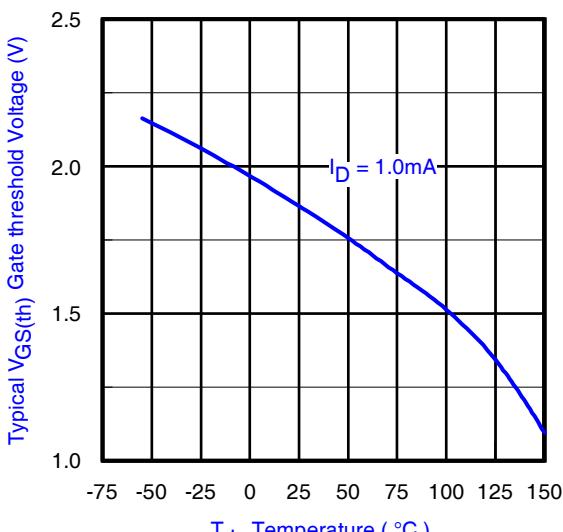


Fig 13. Typical Threshold Voltage vs. Junction Temperature

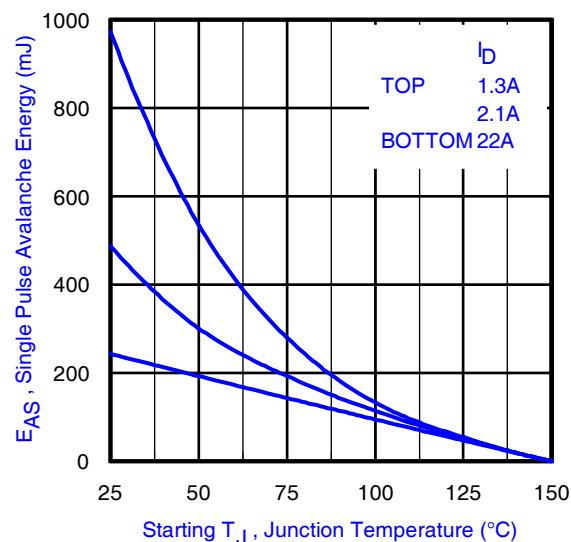


Fig 14. Maximum Avalanche Energy vs. Drain Current

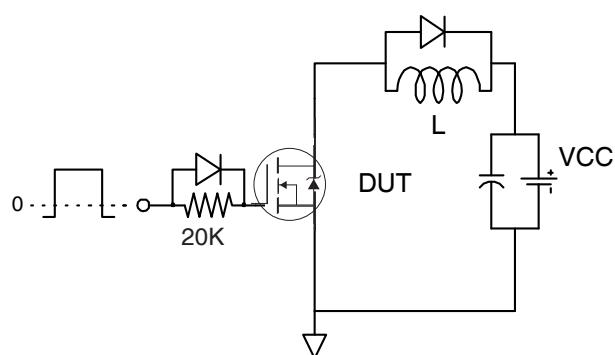


Fig 15a. Gate Charge Test Circuit

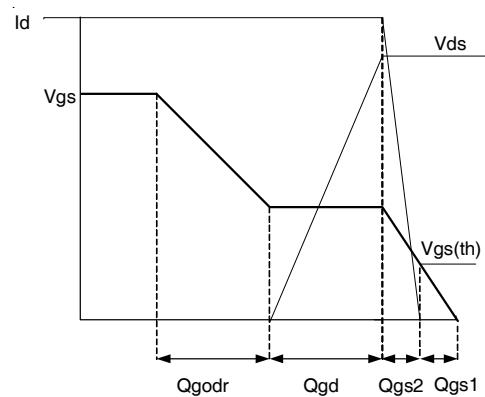


Fig 15b. Gate Charge Waveform

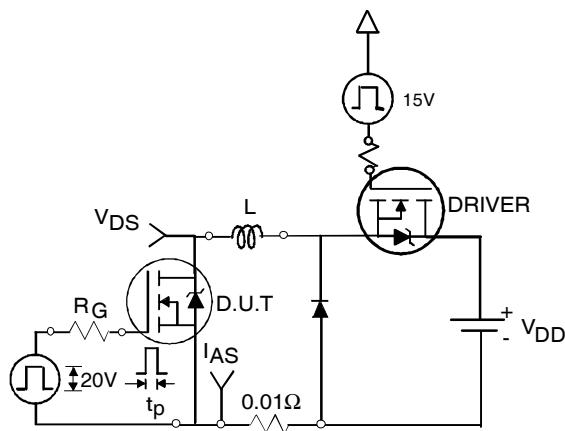


Fig 16a. Unclamped Inductive Test Circuit

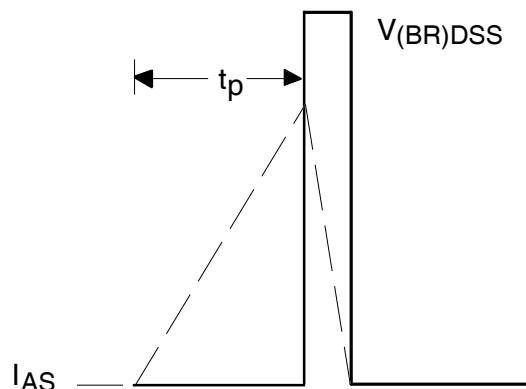


Fig 16b. Unclamped Inductive Waveforms

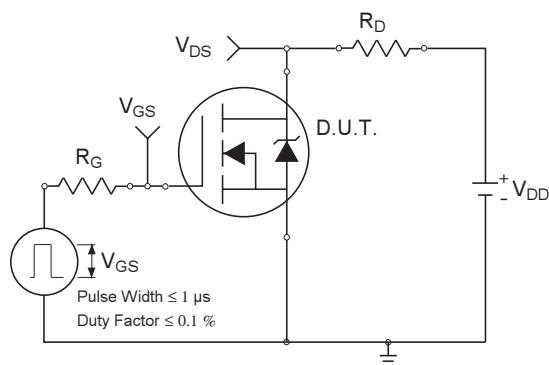


Fig 17a. Switching Time Test Circuit

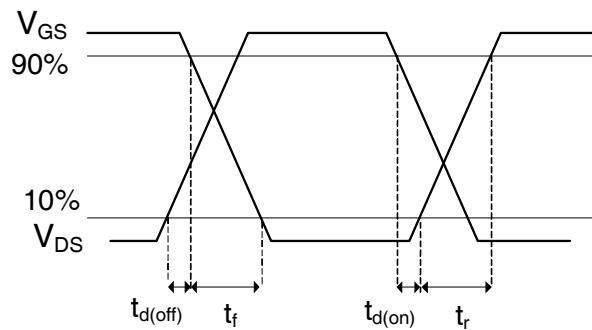


Fig 17b. Switching Time Waveforms

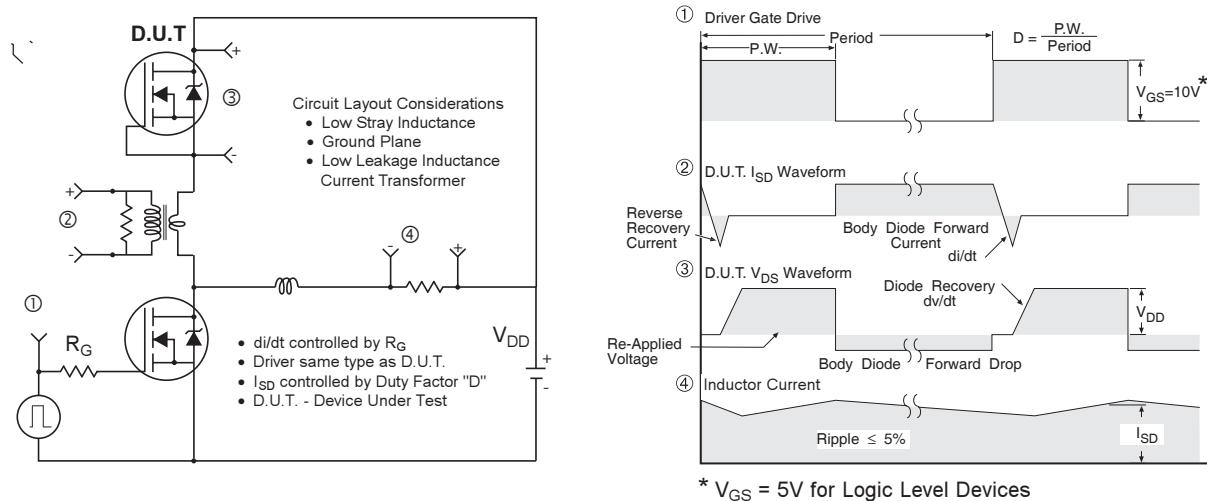
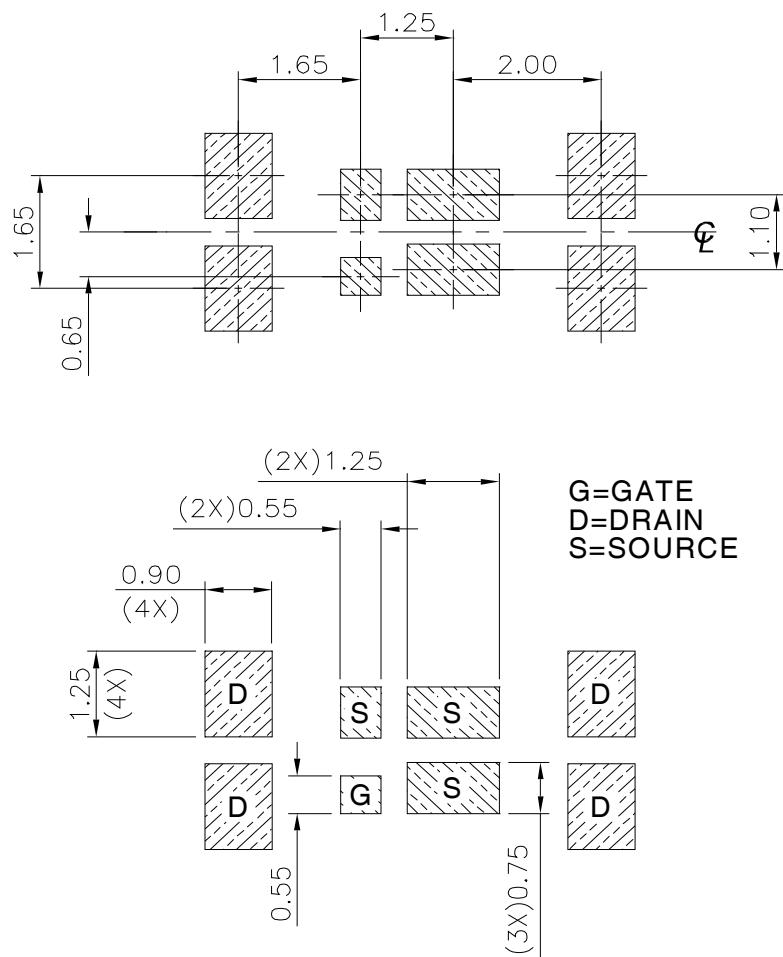


Fig 19. Diode Reverse Recovery Test Circuit for N-Channel
HEXFET® Power MOSFETs

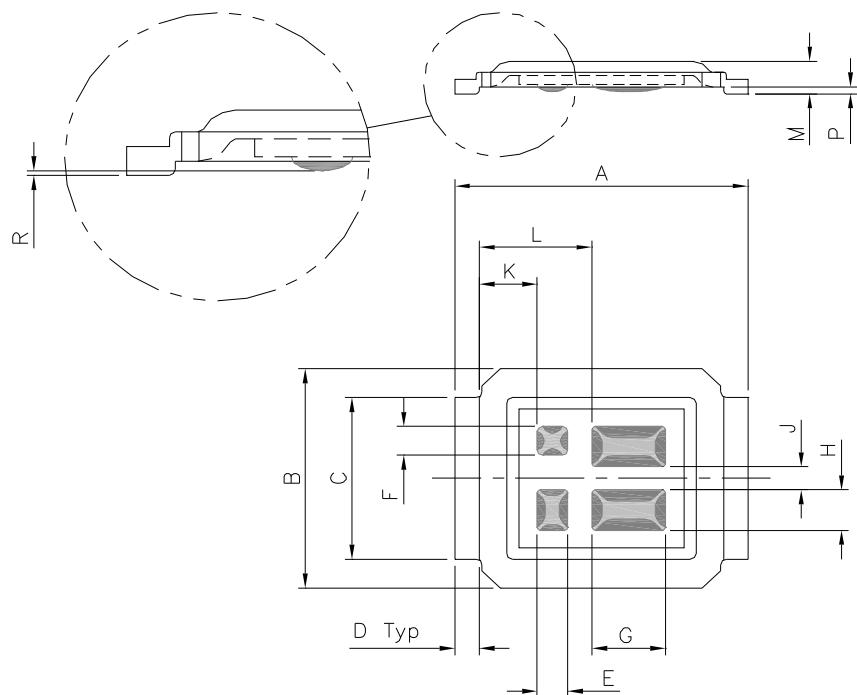
DirectFET®plus Board Footprint, S3C (Small Size Can).

Please see AN-1035 for DirectFET assembly details and stencil and substrate design recommendations

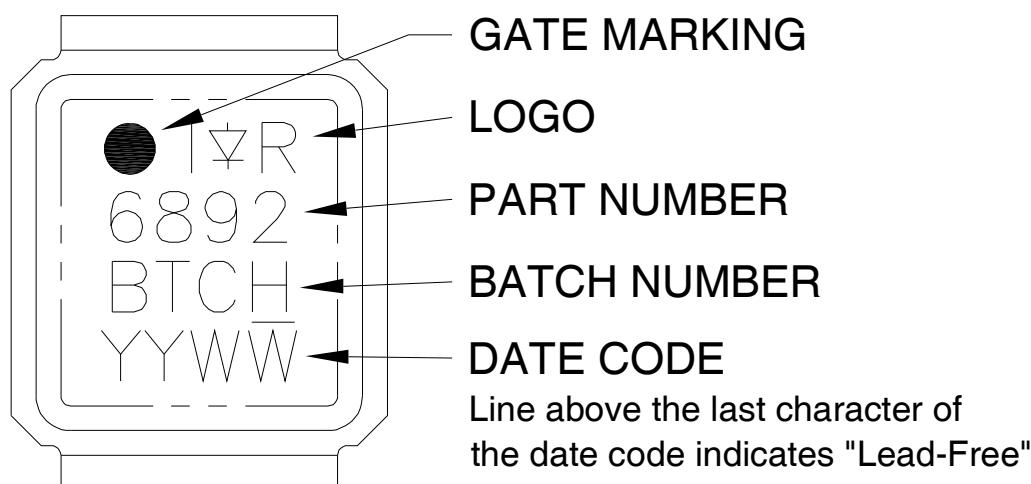


DirectFET®*plus* Outline Dimension, S3C Outline (Small Size Can).

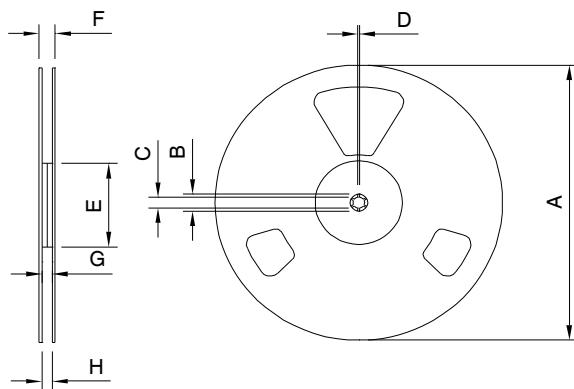
Please see AN-1035 for DirectFET assembly details and stencil and substrate design recommendations



CODE	DIMENSIONS			
	METRIC	IMPERIAL	MIN	MAX
A	4.75	4.85	0.187	0.191
B	3.70	3.95	0.146	0.156
C	2.75	2.85	0.108	0.112
D	0.35	0.45	0.014	0.018
E	0.48	0.52	0.019	0.020
F	0.48	0.52	0.019	0.020
G	1.18	1.22	0.047	0.048
H	0.68	0.72	0.027	0.028
J	0.38	0.42	0.015	0.016
K	0.90	1.00	0.035	0.039
L	1.80	1.90	0.071	0.075
M	0.52	0.62	0.020	0.024
P	0.08	0.17	0.003	0.007
R	0.02	0.08	0.0008	0.0031

DirectFET®*plus* Part Marking

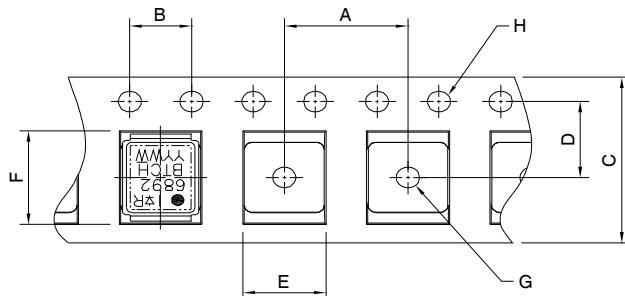
DirectFET®plus Tape & Reel Dimension (Showing component orientation).



NOTE: Controlling dimensions in mm
Std reel quantity is 4800 parts. (ordered as IRF6892STRPBF). For 1000 parts on 7" reel, order IRF6892STR1PBF

REEL DIMENSIONS								
CODE	STANDARD OPTION (QTY 4800)		TR1 OPTION (QTY 1000)		METRIC		IMPERIAL	
	Metric	Imperial	Metric	Imperial	Metric	Imperial	Metric	Imperial
A	330.0	N.C.	12.992	N.C.	177.77	N.C.	6.9	N.C.
B	20.2	N.C.	0.795	N.C.	19.06	N.C.	0.75	N.C.
C	12.8	13.2	0.504	0.520	13.5	12.8	0.53	0.50
D	1.5	N.C.	0.059	N.C.	1.5	N.C.	0.059	N.C.
E	100.0	N.C.	3.937	N.C.	58.72	N.C.	2.31	N.C.
F	N.C.	18.4	N.C.	0.724	N.C.	13.50	N.C.	0.53
G	12.4	14.4	0.488	0.567	11.9	12.01	0.47	N.C.
H	11.9	15.4	0.469	0.606	11.9	12.01	0.47	N.C.

LOADED TAPE FEED DIRECTION



NOTE: CONTROLLING DIMENSIONS IN MM

DIMENSIONS			
	METRIC	IMPERIAL	
CODE	MIN	MAX	MIN
A	7.90	8.10	0.311
B	3.90	4.10	0.154
C	11.90	12.30	0.469
D	5.45	5.55	0.215
E	4.00	4.20	0.158
F	5.00	5.20	0.197
G	1.50	N.C.	0.059
H	1.50	1.60	0.059
			0.063

Note: For the most current drawing please refer to IR website at <http://www.irf.com/package>

Data and specifications subject to change without notice.

This product has been designed and qualified to MSL1 rating for the Consumer market.

Additional storage requirement details for DirectFET products can be found in application note AN1035 on IR's Web site.

Qualification Standards can be found on IR's Web site

International
IR Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

TAC Fax: (310) 252-7903

Visit us at www.irf.com for sales contact information.04/2012

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